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Identification cards — Test methods —

Part 3:

Integrated circuit cards with contacts and related interface devices

Cartes d'identification — Méthodes d'essai —

Partie 3: Cartes à circuit(s) intégré(s) à contacts et dispositifs d'interface assimilés

Reference number
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Foreword

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The main task of the joint technical committee is to prepare International Standards. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

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ISO/IEC 10373-3 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

This second edition cancels and replaces the first edition (ISO/IEC 10373-3:2001), which has been technically revised.

ISO/IEC 10373 consists of the following parts, under the general title *Identification cards — Test methods*:

- *Part 1: General characteristics*
- *Part 2: Cards with magnetic stripes*
- *Part 3: Integrated circuit cards with contacts and related interface devices*
- *Part 5: Optical memory cards*
- *Part 6: Proximity cards*
- *Part 7: Vicinity cards*
- *Part 8: USB-ICC*

The following part is under preparation:

- *Part 9: Optical memory cards: Holographic recording method*